

# International IOR Rectifier

SMPS MOSFET

# IRFIB7N50L

PD - 95888

HEXFET® Power MOSFET

### Applications

- Zero Voltage Switching SMPS
- Telecom and Server Power Supplies
- Uninterruptible Power Supplies
- Motor Control applications

V <sub>DSS</sub>	R <sub>DS(on) typ.</sub>	T <sub>rr typ.</sub>	I <sub>D</sub>
500V	320mΩ	85ns	6.8A

### Features and Benefits

- SuperFast body diode eliminates the need for external diodes in ZVS applications.
- Lower Gate charge results in simpler drive requirements.
- Enhanced dv/dt capabilities offer improved ruggedness.
- Higher Gate voltage threshold offers improved noise immunity.



### Absolute Maximum Ratings

Parameter	Max.	Units
I <sub>D</sub> @ T <sub>C</sub> = 25°C	6.8	A
I <sub>D</sub> @ T <sub>C</sub> = 100°C	4.3	
I <sub>DM</sub>	27	
P <sub>D</sub> @ T <sub>C</sub> = 25°C	46	W
	0.37	W/°C
V <sub>GS</sub>	±30	V
dv/dt	24	V/ns
T <sub>J</sub>	-55 to +150	°C
T <sub>STG</sub>		
	300 (1.6mm from case )	
	10lb·in (1.1N·m)	

### Diode Characteristics

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
I <sub>S</sub>	Continuous Source Current (Body Diode)	—	—	6.8	A	MOSFET symbol showing the integral reverse p-n junction diode.
I <sub>SM</sub>	Pulsed Source Current (Body Diode) ①	—	—	27		
V <sub>SD</sub>	Diode Forward Voltage	—	—	1.5	V	T <sub>J</sub> = 25°C, I <sub>S</sub> = 6.8A, V <sub>GS</sub> = 0V ④
t <sub>rr</sub>	Reverse Recovery Time	—	85	130	ns	T <sub>J</sub> = 25°C, I <sub>F</sub> = 6.8A
		—	130	200		T <sub>J</sub> = 125°C, di/dt = 100A/μs ④
Q <sub>rr</sub>	Reverse Recovery Charge	—	280	420	nC	T <sub>J</sub> = 25°C, I <sub>S</sub> = 6.8A, V <sub>GS</sub> = 0V ④
		—	570	860		T <sub>J</sub> = 125°C, di/dt = 100A/μs ④
I <sub>RRM</sub>	Reverse Recovery Current	—	5.9	8.9	A	T <sub>J</sub> = 25°C
t <sub>on</sub>	Forward Turn-On Time	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)				



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## Static @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source Breakdown Voltage	500	—	—	V	$V_{GS} = 0V, I_D = 250\mu A$
$\Delta V_{(BR)DSS}/\Delta T_J$	Breakdown Voltage Temp. Coefficient	—	0.44	—	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}, I_D = 1\text{mA}$
$R_{DS(on)}$	Static Drain-to-Source On-Resistance	—	0.32	0.38	$\Omega$	$V_{GS} = 10V, I_D = 4.1A$ ④
$V_{GS(th)}$	Gate Threshold Voltage	3.0	—	5.0	V	$V_{DS} = V_{GS}, I_D = 250\mu A$
$I_{DSS}$	Drain-to-Source Leakage Current	—	—	50	$\mu A$	$V_{DS} = 500V, V_{GS} = 0V$
		—	—	2.0	mA	$V_{DS} = 400V, V_{GS} = 0V, T_J = 125^\circ\text{C}$
$I_{GSS}$	Gate-to-Source Forward Leakage	—	—	100	nA	$V_{GS} = 30V$
	Gate-to-Source Reverse Leakage	—	—	-100	nA	$V_{GS} = -30V$
$R_G$	Internal Gate Resistance	—	0.88	—	$\Omega$	$f = 1\text{MHz}, \text{open drain}$

## Dynamic @ $T_J = 25^\circ\text{C}$ (unless otherwise specified)

Symbol	Parameter	Min.	Typ.	Max.	Units	Conditions
$g_{fs}$	Forward Transconductance	4.7	—	—	S	$V_{DS} = 50V, I_D = 4.1A$
$Q_g$	Total Gate Charge	—	—	92	nC	$I_D = 6.8A$ $V_{DS} = 400V$ $V_{GS} = 10V, \text{See Fig. 7 \& 16 } \text{④}$
$Q_{gs}$	Gate-to-Source Charge	—	—	24		
$Q_{gd}$	Gate-to-Drain ("Miller") Charge	—	—	44		
$t_{d(on)}$	Turn-On Delay Time	—	23	—	ns	$V_{DD} = 250V$ $I_D = 6.8A$ $R_G = 9.0\Omega$ $V_{GS} = 10V, \text{See Fig. 11a \& 11b } \text{④}$
$t_r$	Rise Time	—	36	—		
$t_{d(off)}$	Turn-Off Delay Time	—	47	—		
$t_f$	Fall Time	—	19	—		
$C_{iss}$	Input Capacitance	—	2220	—	pF	$V_{GS} = 0V$ $V_{DS} = 25V$ $f = 1.0\text{MHz}, \text{See Fig. 5}$ $V_{GS} = 0V, V_{DS} = 1.0V, f = 1.0\text{MHz}$ $V_{GS} = 0V, V_{DS} = 400V, f = 1.0\text{MHz}$ $V_{GS} = 0V, V_{DS} = 0V \text{ to } 400V \text{ } \text{⑤}$
$C_{oss}$	Output Capacitance	—	230	—		
$C_{rss}$	Reverse Transfer Capacitance	—	23	—		
$C_{oss}$	Output Capacitance	—	2780	—		
$C_{oss}$	Output Capacitance	—	63	—		
$C_{oss \text{ eff.}}$	Effective Output Capacitance	—	140	—		
$C_{oss \text{ eff. (ER)}}$	Effective Output Capacitance (Energy Related)	—	100	—		

## Avalanche Characteristics

Symbol	Parameter	Typ.	Max.	Units
$E_{AS}$	Single Pulse Avalanche Energy ②	—	550	mJ
$I_{AR}$	Avalanche Current ①	—	6.8	A
$E_{AR}$	Repetitive Avalanche Energy ①	—	4.6	mJ

## Thermal Resistance

Symbol	Parameter	Typ.	Max.	Units
$R_{\theta JC}$	Junction-to-Case	—	2.69	$^\circ\text{C/W}$
$R_{\theta JA}$	Junction-to-Ambient	—	65	

### Notes:

- ① Repetitive rating; pulse width limited by max. junction temperature. (See Fig. 12).
- ② Starting  $T_J = 25^\circ\text{C}$ ,  $L = 24\text{mH}$ ,  $R_G = 25\Omega$ ,  $I_{AS} = 6.8A$ , (See Figure 14).
- ③  $I_{SD} \leq 6.8$ ,  $di/dt \leq 650A/\mu s$ ,  $V_{DD} \leq V_{(BR)DSS}$ ,  $dv/dt = 24V/ns$ ,  $T_J \leq 150^\circ\text{C}$ .

④ Pulse width  $\leq 300\mu s$ ; duty cycle  $\leq 2\%$ .

- ⑤  $C_{oss \text{ eff.}}$  is a fixed capacitance that gives the same charging time as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .  
 $C_{oss \text{ eff. (ER)}}$  is a fixed capacitance that stores the same energy as  $C_{oss}$  while  $V_{DS}$  is rising from 0 to 80%  $V_{DSS}$ .

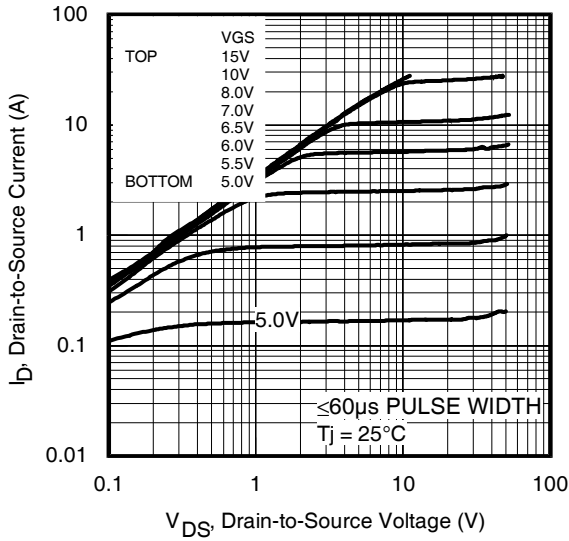


Fig 1. Typical Output Characteristics

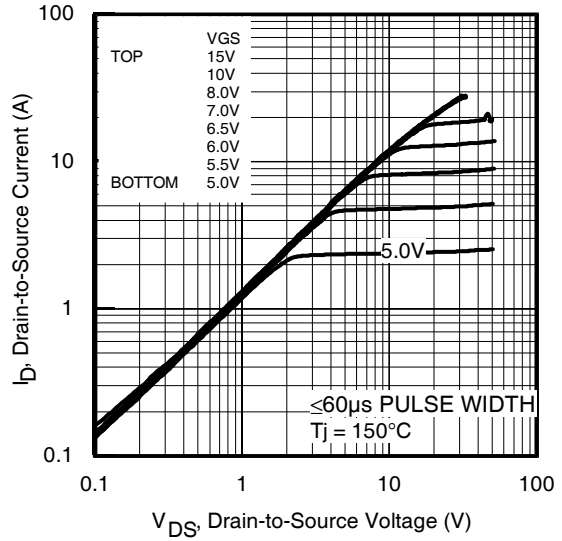


Fig 2. Typical Output Characteristics

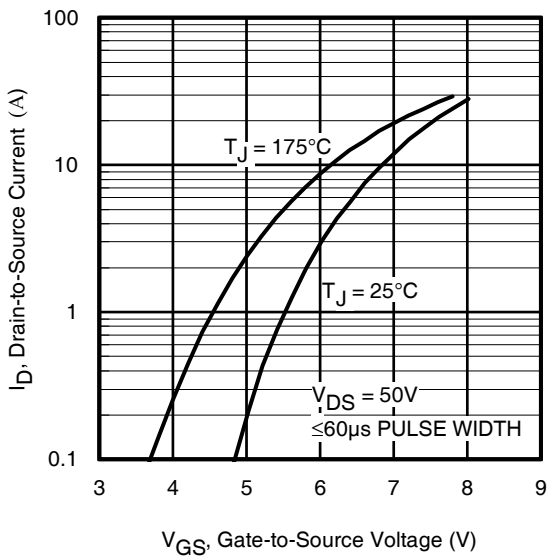


Fig 3. Typical Transfer Characteristics

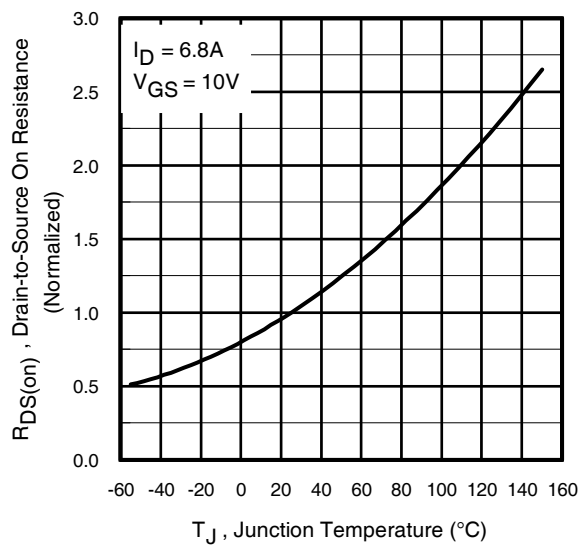
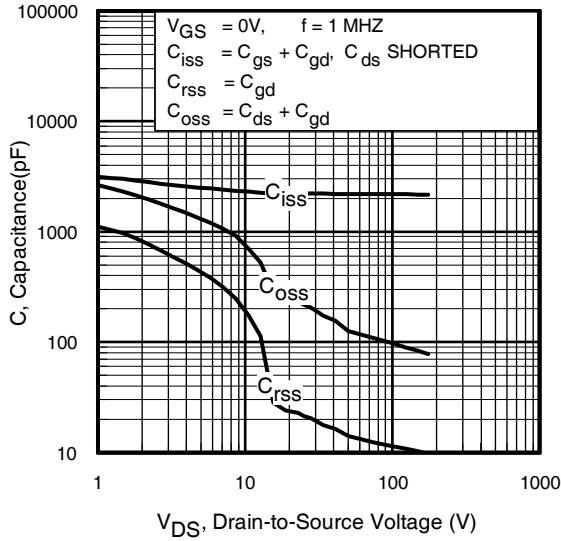
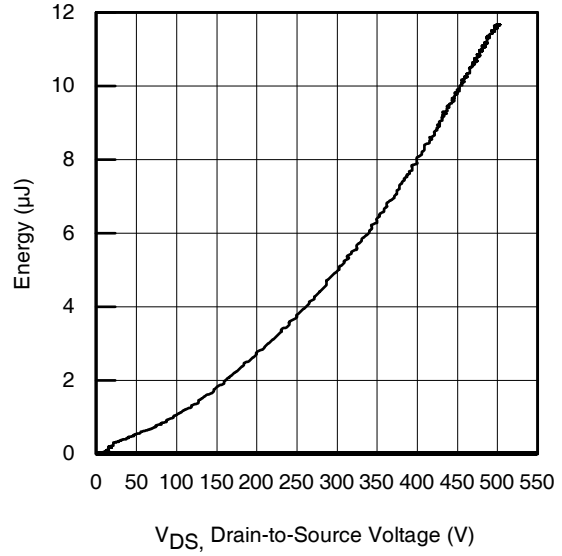


Fig 4. Normalized On-Resistance vs. Temperature

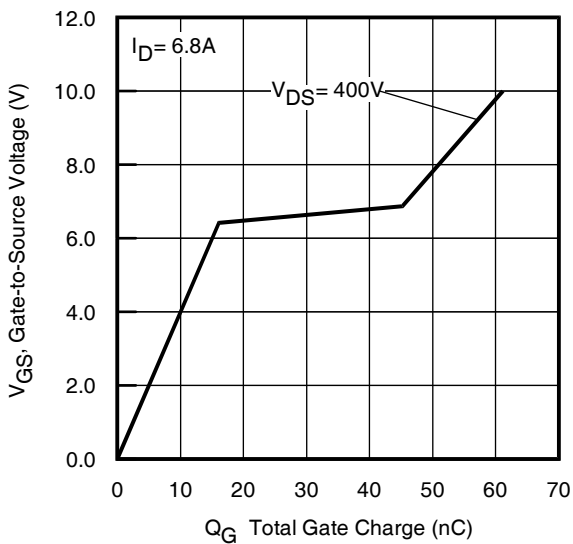
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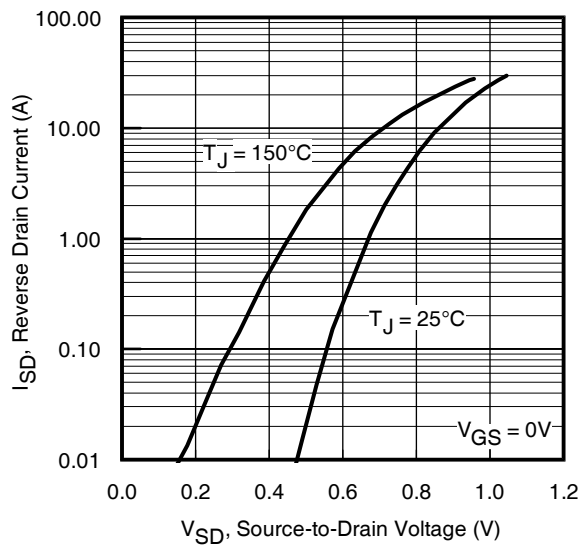
**Fig 5.** Typical Capacitance vs. Drain-to-Source Voltage



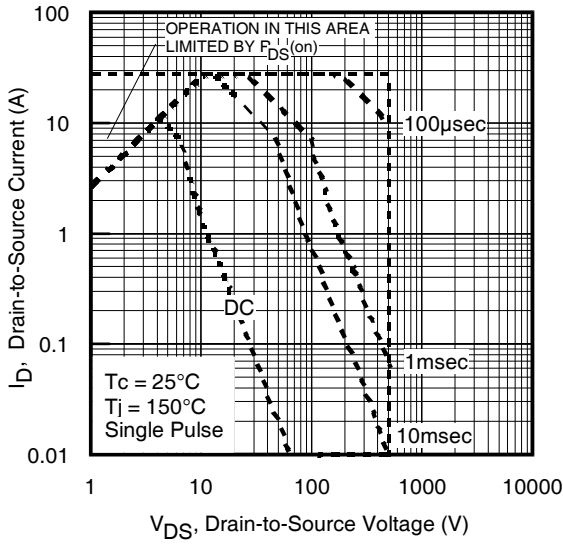
**Fig 6.** Typ. Output Capacitance Stored Energy vs.  $V_{DS}$



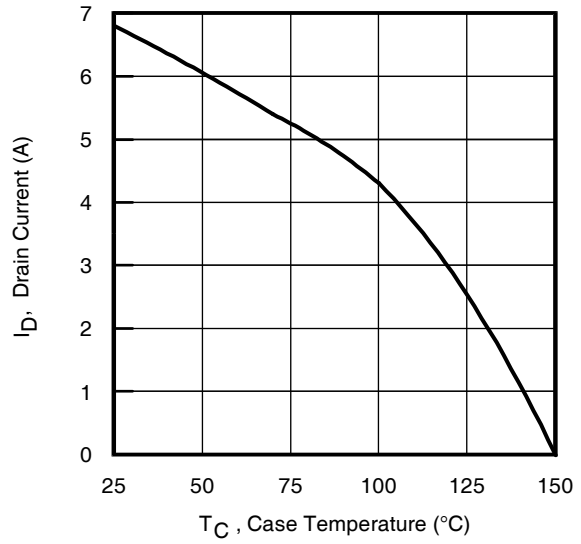
**Fig 7.** Typical Gate Charge vs. Gate-to-Source Voltage



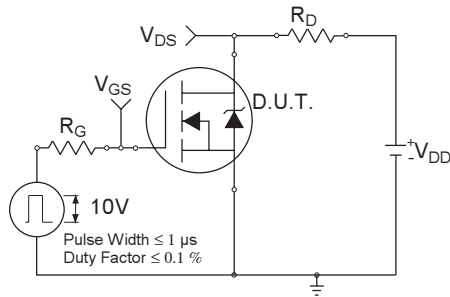
**Fig 8.** Typical Source-Drain Diode Forward Voltage



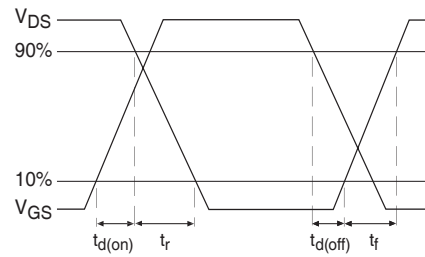
**Fig 9.** Maximum Safe Operating Area



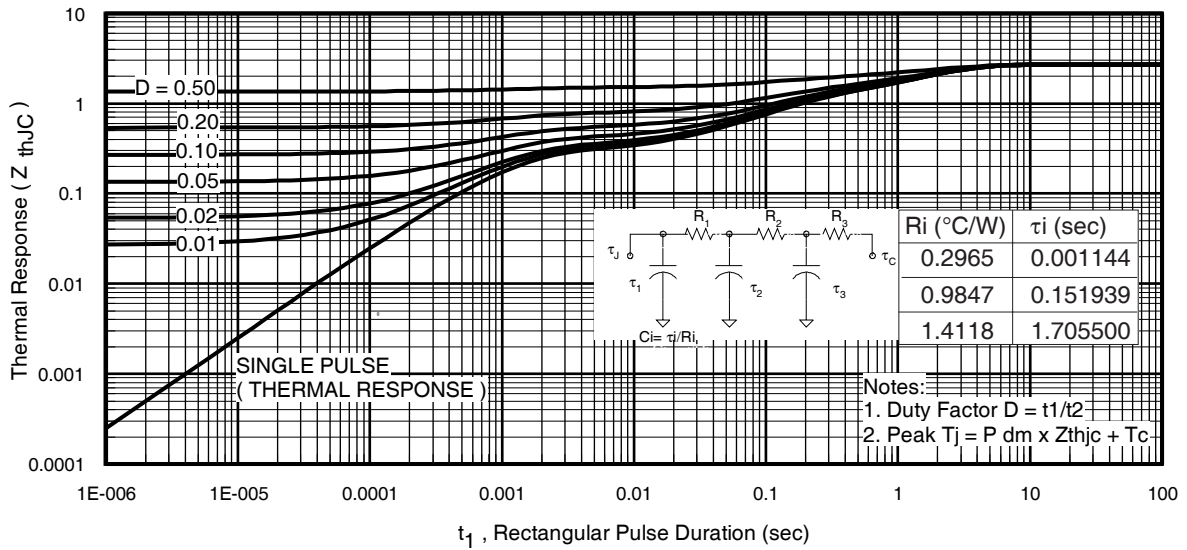
**Fig 10.** Maximum Drain Current vs. Case Temperature



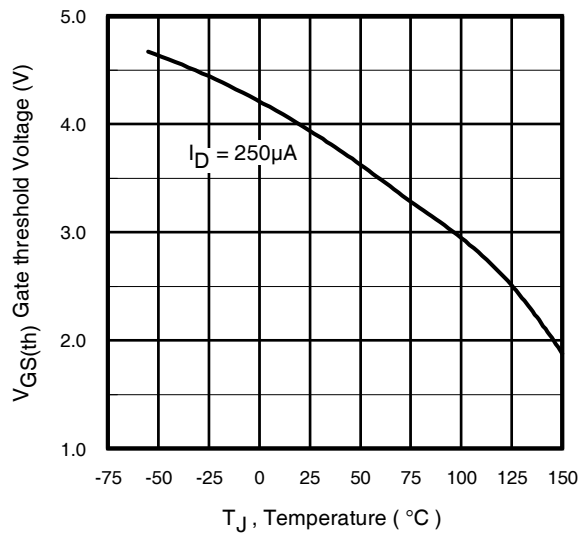
**Fig 11a.** Switching Time Test Circuit



**Fig 11b.** Switching Time Waveforms



**Fig 12.** Maximum Effective Transient Thermal Impedance, Junction-to-Case



**Fig 13.** Threshold Voltage vs. Temperature

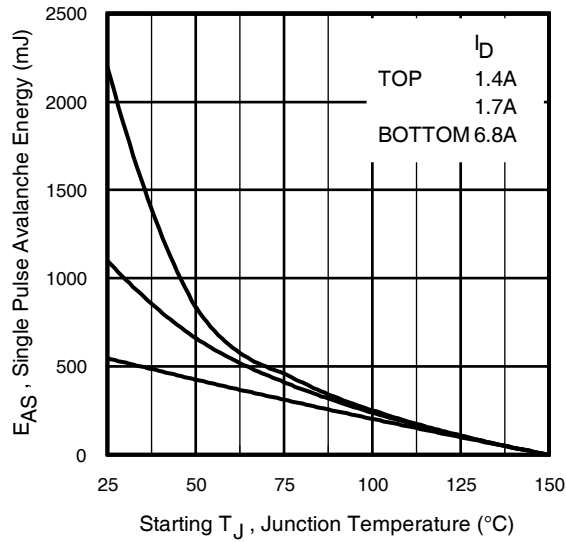


Fig 14. Maximum Avalanche Energy vs. Drain Current

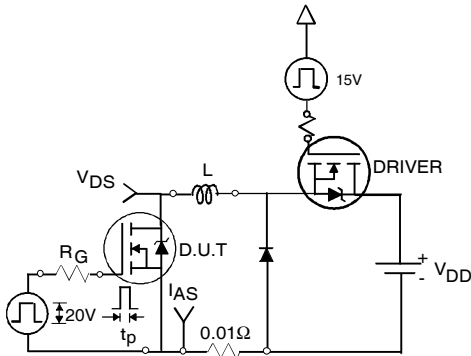


Fig 15a. Unclamped Inductive Test Circuit

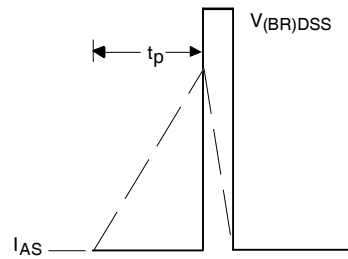


Fig 15b. Unclamped Inductive Waveforms

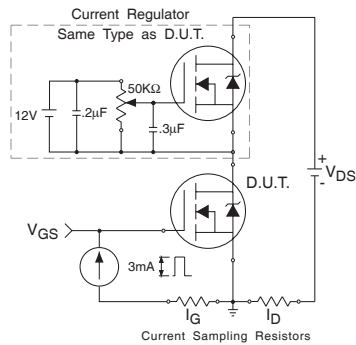


Fig 16a. Gate Charge Test Circuit  
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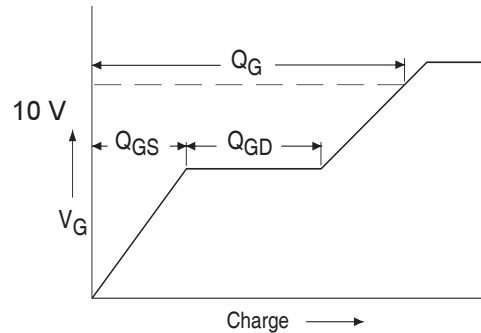
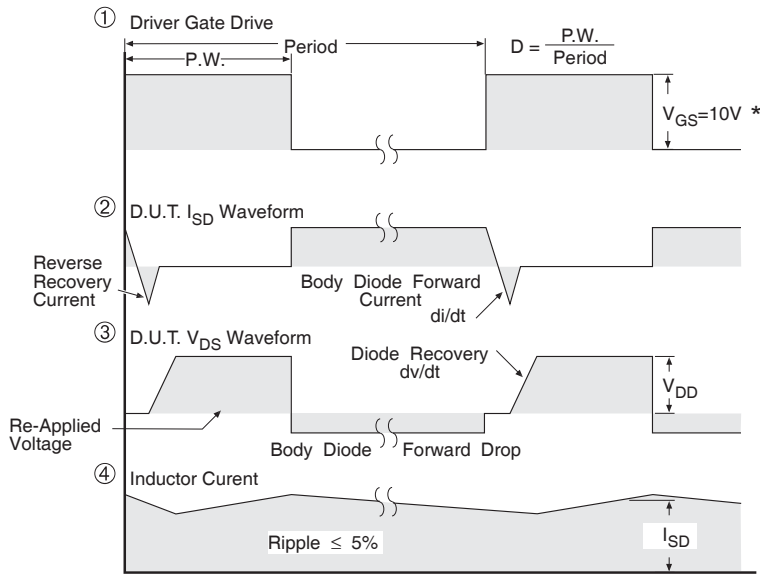
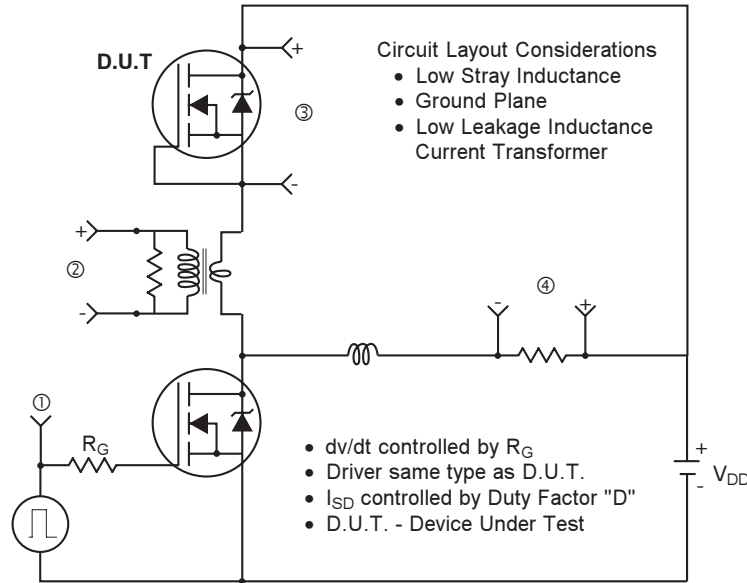


Fig 16b. Basic Gate Charge Waveform

## Peak Diode Recovery dv/dt Test Circuit



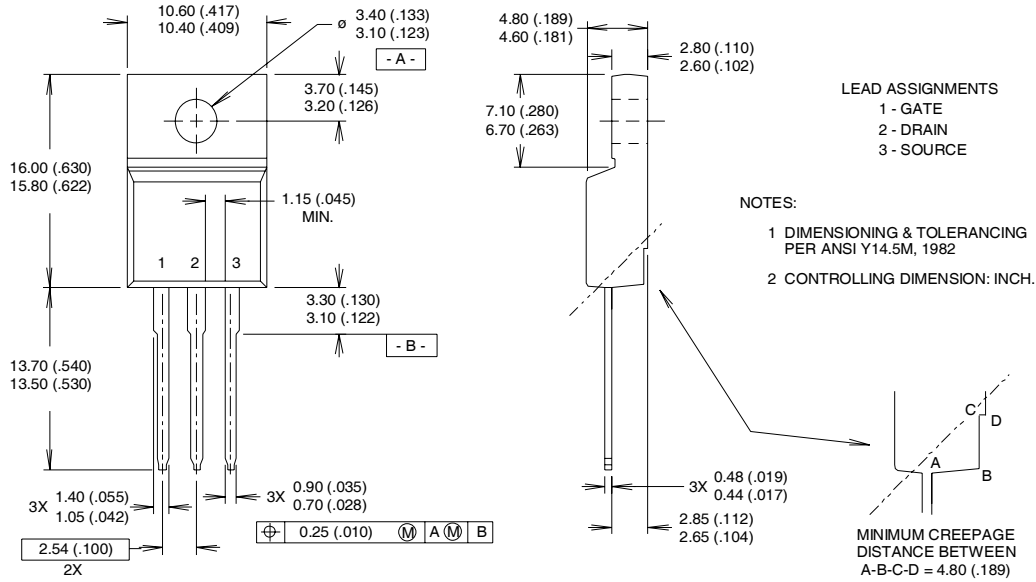
\*  $V_{GS} = 5V$  for Logic Level Devices

**Fig 17.** For N-Channel HEXFET® Power MOSFETs



## TO-220 Full-Pak Package Outline

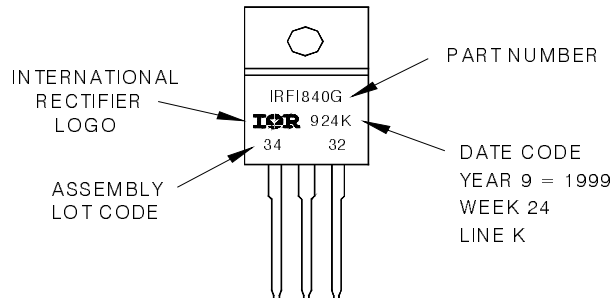
Dimensions are shown in millimeters (inches)



## TO-220 Full-Pak Part Marking Information

EXAMPLE: THIS IS AN IRFI840G  
 WITH ASSEMBLY  
 LOT CODE 3432  
 ASSEMBLED ON WW 24 1999  
 IN THE ASSEMBLY LINE "K"

**Note:** "P" in assembly line position indicates "Lead-Free"



**TO-220AB FullPak package is not recommended for Surface Mount Application.**

Data and specifications subject to change without notice.  
 This product has been designed and qualified for the Industrial market.  
 Qualification Standards can be found on IR's Web site.